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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
Stylesheet Version v18.0

Title of Invention

METHODS AND SYSTEMS FOR INSPECTION OF AN ENTIRE WAFER SURFACE USING MULTIPLE DETECTION CHANNELS

Application Number:

10/663603

Confirmation Number: 3534

First Named Applicant:

Lionel Kuhlmann

Attorney Docket Number: 5589-06100

Search string:

(6271916 or 6204917 or 6559938 or 6201601 or 6538730 or 6509965 or 6507394 or 6356346 or 6020957 or 5355212 or 6407809 or 6515742 or 6496256 or 6034776 or 5999266 or 5801824 or 5623340 or 5604585 or 5585916 or 4632546

or 20030030050 or 20030030795 or 20020149765 or 20020145732 or

20010028454).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
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	2	6204917	2001-03-20	Smedt			
	3	6559938	2003-05-06	Smedt			
	4	6201601	2003-03-13	Vaez-Iravani et al.			
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	6	6509965	2003-01-21	Fossey et al.			
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	8	6356346	2002-03-12	Hagen et al.			
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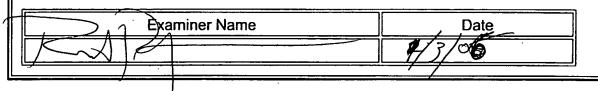
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2	15	5999266	1999-12-07	Takahashi et al.
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US Published Applications

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	2	20030030795	2003-02-13	Swan et al.			
	3	20020149765	2003-10-17	Fujii et al.			
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Signature



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Page 1 of 1

Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement			TY. DKT. NO. 5589-06100		SEF	SERIAL NO. 10/663,603			
List of Patents and Publications For Applicant's Information			APPLICANT: Kuhlmann et al.			GROUP: 2877			
			511 NIO DATE O						
(Use several sheets if necessary) FILING DATE: September 16, 2003									
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